

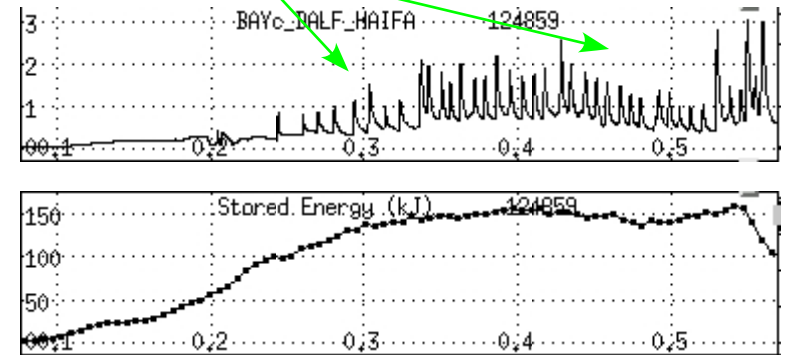
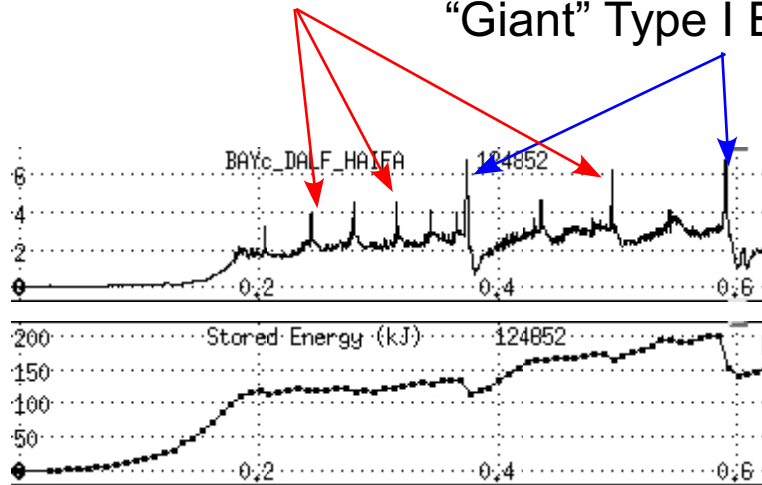
# XP745: Relationship of ELM Severity and Electron Transport

## Successfully Generated Type I ELMs $\Delta W_{\text{tot}} \sim 1\text{-}30\%$

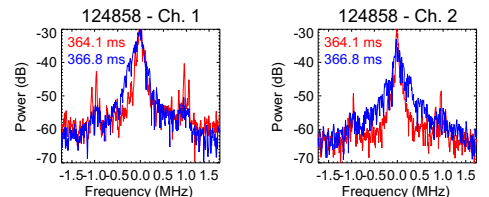
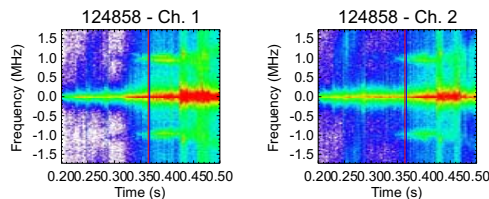
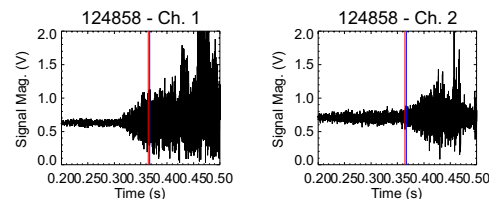
“Medium” Type I ELMs  $\sim 5\text{-}10\%$

“Giant” Type I ELMs  $\sim 15\text{-}30\%$

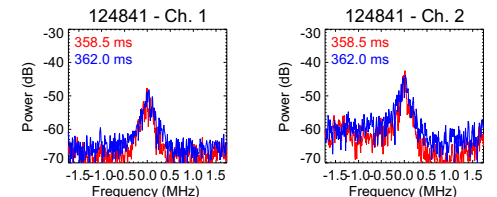
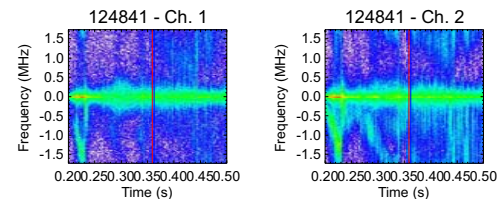
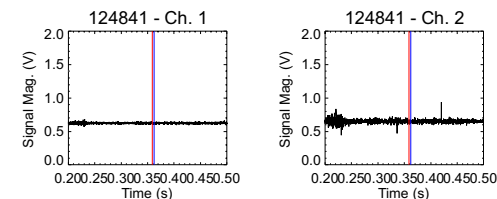
“Small” Type I ELMs  $\sim 1\text{-}5\%$



High-k measurements at 135cm were over-attenuated



117cm ← 135cm →



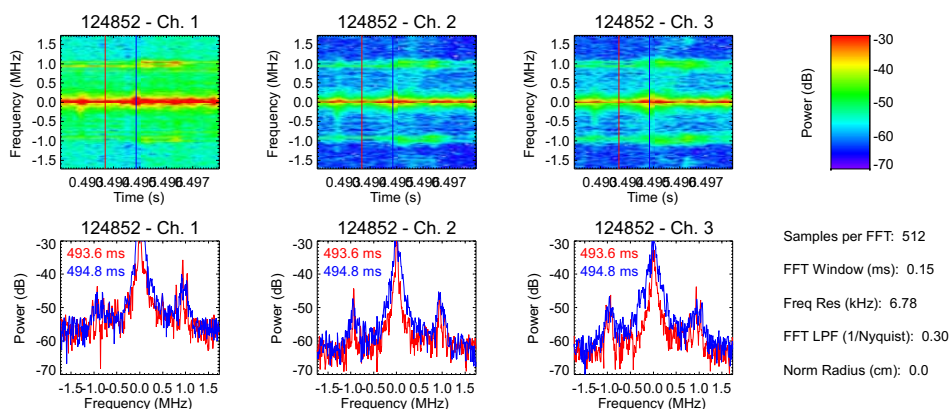
Samples per FFT: 512  
FFT Window (ms): 0.15  
Freq Res (kHz): 6.78  
FFT LPF (1/Nyquist): 0.30  
Norm Radius (cm): 0.0

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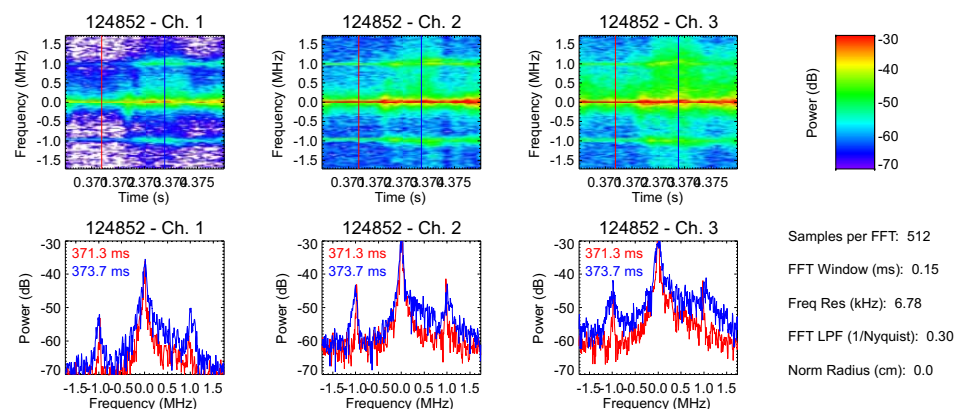
# USXR and High-k Data Indicate Differences Corresponding to ELM Severity

## High-k Data

$\Delta W_{\text{tot}} \sim 6\text{-}8\%$



$\Delta W_{\text{tot}} \sim 16\text{-}20\%$



## USXR Data - Be100u Filter

